IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re	Application of:)	
		:	Examiner: K.L. Rose
MITS	SUTOSHI HASEGAWA, ET AL.)	
		:	Group Art Unit: 2822
Appl	ication No.: 10/647,287)	
-		:	Confirmation No. 2681
Filed	: August 26, 2003)	
		:	
For:	ENVELOPE, ENVELOPE)	
	MANUFACTURING METHOD,	:	
	IMAGE DISPLAY DEVICE, AND)	
	TELEVISION DISPLAY	:	November 16, 2007

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

SECOND REQUEST FOR CONSIDERATION OF REFERENCES CITED IN FORM PTO 1449

Sir:

Attached to the Office Action of June 6, 2005 was a returned copy of a Form PTO 1449 that was filed with the Information Disclosure Statement on January 14, 2004. The documents listed under "Foreign Patent Documents" and "Other Document(s)" were not initialed, apparently because the Patent Office does not have copies of those documents in the present application. A copy of that returned Form PTO 1449 is attached hereto.

Applicants provided additional copies of those documents with its first

Request for Consideration of References Cited in Form PTO 1449 ("Request") filed in the

Patent and Trademark Office on October 4, 2007. Attached is a copy of that Request with the Patent and Trademark Office's stamp of receipt thereon. Applicants, once again, respectfully request that Form PTO 1449 be initialed and returned by the Examiner

indicating she has considered those references.

If a fee is required to have the mentioned references considered by the Examiner, please charge any such fee to Deposit Account 06-1205.

Applicants' undersigned attorney may be reached in our New York Office by telephone at (212) 218-2100. All correspondence should continue to be directed to our

Respectfully submitted,

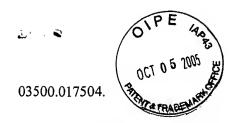
/Frank A. DeLucia/ Frank A. DeLucia Attorney for Applicants Registration No. 42,476

FITZPATRICK, CELLA, HARPER & SCINTO 30 Rockefeller Plaza New York, New York 10112-3801 Facsimile: (212) 218-2200

FCHS_WS 1744611v1

address listed below.





PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re App	lication of:)	
-		;	Examiner: K.L. Rose
MITSUT	OSHI HASEGAWA, ET AL.)	
		:	Group Art Unit: 2822
Applicati	on No.: 10/647,287)	
		:	
Filed: Au	gust 26, 2003)	
		:	
For: EN	IVELOPE, ENVELOPE)	
	ANUFACTURING METHOD,	:	
IM	AGE DISPLAY DEVICE, AND) .	
TE	LEVISION DISPLAY	:	October 4, 2005

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

REQUEST FOR CONSIDERATION OF REFERENCES CITED IN FORM PTO 1449

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Attached to the Office Action of June 6, 2005 was a returned copy of a Form PTO 1449 that was filed with the Information Disclosure Statement on January 14, 2004. The documents listed under "Foreign Patent Documents" and "Other Document(s)" were not initialled, apparently because the Patent Office does not have copies of those documents in the present application. A copy of that returned Form PTO 1449 is attached hereto.

Applicants hereby provide additional copies of those documents, which are listed (but not initialled) on the enclosed Form PTO 1449. Applicants respectfully request

that Form PTO 1449 be initialed and returned by the Examiner indicating he has considered those references.

If a fee is required to have the mentioned references considered by the Examiner, please charge any such fee to Deposit Account 06-1205.

Applicants' undersigned attorney may be reached in our New York Office by telephone at (212) 218-2100. All correspondence should continue to be directed to our address listed below.

Respectfully submitted,

Antorney for Applicants

Frank A. DeLucia

Registration No. 42,476

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	S (Use s	several sheets if necessary)		FILI	ING DATE August 26, 2003		GROUP n/s	JP n/y/a	
PRADEMARY				100	PATENT DOCUMENTS		10)	// 0	
'EXAMINER DOCUMENT INITIAL NUMBER DATE				NAME	CLASS	SUBCLASS	FILING DATE		
KR		6,060,113	05/00)	Banno et al.	427	125		
		6,296,896 B1	10/01	1	Takahashi et al.	427	77		
		2003/0067263 A1	04/03	3	Tokioka et al.	313	493	08/28/02	
		6,624,586 B2	09/03	3	Abe et al.	315	169.1		
		5,455,597	10/9	5	Nakamura et al.	345	75		
		5,659,329	. 08/97	7	Yamanobe et al.	345	74		
KR		6,137,218	10/0	0 Kaneko et al.		313	495		
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		DOCUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
V	JP	7-326311	12/9	5	Japan			Abstract	
<i></i>	JP	8-185818	07/9	6	Japan			Abstract	
/	, JP	9-50757	02/9	<u></u>	Japan			Abstract	
	JP	9-102271	04/9	7	Japan			Abstract	
	"	2000-251665	. 9/00)	Japan			Abstract	
		OTHER C	OCUMENT(S	i) (Incl	duding Author, Title, Date, Pertinent Pages, Etc.)				
	M. Hartwell et al, "Strong electron emission from patterned tin-indium oxide thin films", International Electron Devices Meeting 1975, Washington, D.C., Catalog No. 75, CH1023-1, IEDM Technical Digest. pp. 519-521.								
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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2004	8)	veral sheets if necessary)		FILING DATE August 26,	2003	GROUP n/y/a				
\@	\$		U.S. F	PATENT DOCUMENTS						
- EXAMPLE - INITIAL	DOCUMENT NUMBER DATE			NAME	CLASS	SUBCLASS	FILING DATE FAPPROPRIATE			
KR		6,254,449 B1	07/01	Nakanishi et al.	445	25	08/98			
		6,283,813 B1	09/01	Kaneko et al.	445	24				
		2002/0180342 A1	12/02	Yamada et al.	313	493	07/02			
		6,506,089 B2	01/03	Nakanishi et al.	445	25	02/01			
KR		2003/0058192 A1	03/03	Arai et al.	345	59	09/02			
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT			
	JP	64-31332	2/89	Japan			Abstract			
	JР	6-342636	12/94	Japan			Abstract			
	JP	11-135018	05/99	Japan			Abstract			
	JPP	2001-210258	8/01	Japan			Abstract			
	, ,	OTHER DOC	JMENT(S) (Inc	duding Author, Title, Date, Pertine	ent Pages, Etc.)					
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TOPMS TE 149 (modified)				ATTY DOCKET NO. 03500.017504		APPLICATION NO. 10/647,287			
AN 1.4 THE OF REFERENCES CITED BY APPLICANT(S) William II.4 (Use several sheets if necessary)				APPLICANTS MITSUTOSHI HASEGAWA ET AL.					
				FIL	FILING DATE August 26, 2003 GROUP			n/y/a	
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EXAMINER DOCUMENT NUMBER DATE				NAME	CLAS	S SUBCLASS	FILING DATE IF APPROPRIATE		
KR		6,060,113	05/00	0	Banno et al.	427	7 125		
		6,296,8 9 6 B1	10/0	1	Takahashi et al.	427	7 77		
		2003/0067263 A1	04/0	3	Tokioka et al.	313	3 493	08/28/02	
		6,624,586 B2	09/0	3	Abe et al.	31	5 169.1		
		5,455,597	10/9	5	Nakamura et al.	34	5 75		
		5,659,329	08/9	7	Yamanobe et al.	34	5 74		
KR	<u> </u>	6,137,218	10/0	0	Kaneko et al.	31	3 495		
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		DOCUMENT NUMBER	DATE	E	COUNTRY	CLA	SS SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
	JP 7-326311 12/9		5	5 Japan			Abstract		
	JP	8-185818	07/9	6 Japan				Abstract	
	JP	9-50757	02/9	7 Japan				Abstract	
	JP 9-102271 04/9		7	7 Japan			Abstract		
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		OTHER D	OCUMENT(S) (Inc	cluding Author, Title, Date, Pertinent Pages, Etc.)				
	M. Hartwell et al, "Strong electron emission from patterned tin-indium oxide thin films", International Electron Devices Meeting 1975, Washington, D.C., Catalog No. 75, CH1023-1, IEDM Technical Digest, pp. 619-521.								

EXAMINER	XII.	Shoow			DATE CONSIDERED 45	15			

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HIST OF ACCEPENCES CITED BY ADDITIONALLYS				APPLICANT MITSUTOSHI HASEGAWA ET AL.						
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G. A. C.	8		U.S. F	PATENT DOCUMENTS						
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		6,283,813 B1	09/01	Kaneko et al.	445	24	· · · · · · · · · · · · · · · · · · ·			
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	JР	6-342636	12/94	Jápan	•		Abstract			
	JP	11-135018	05/99	Japan			Abstract			
	JPP	2001-210258	8/01	Japan			. Abstract			
·		OTHER DOCU	JMENT(S) (Inc	luding Author, Title, Date, Pertine	nt Pages, Etc.)					
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